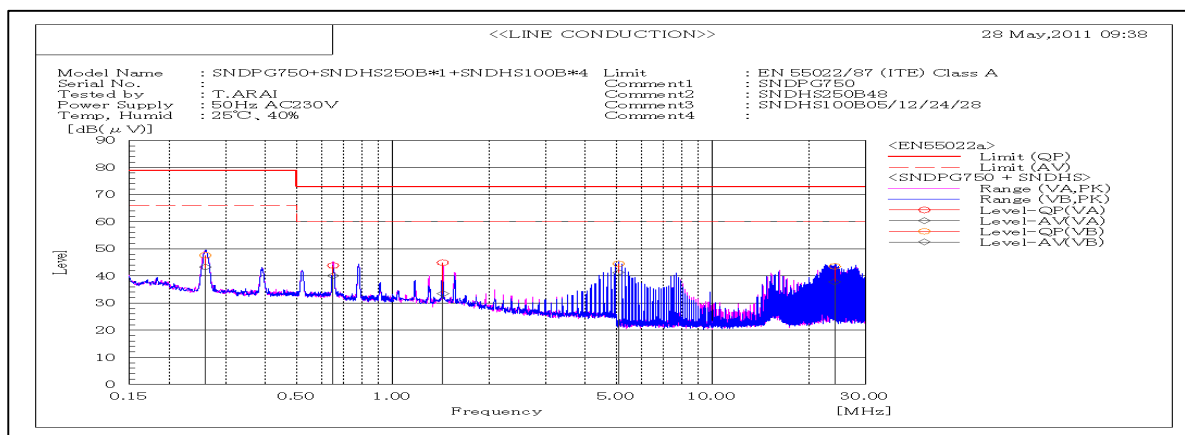
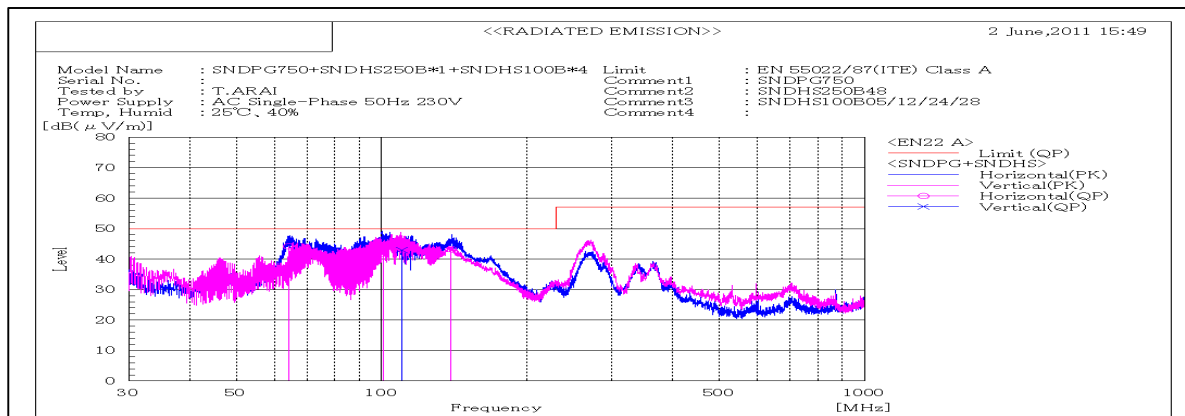


DATA SHEET

Model	SNDPG750 + SNDHS250Bx1(48V) + SNDHS100Bx4(5/12/24/28V)	Date	20-Jul-11
Test	EMI Line conduction & Radiated emission	Temp.	25 degreeC
		Humid.	40 %RH
		Tested by	T.ARAI



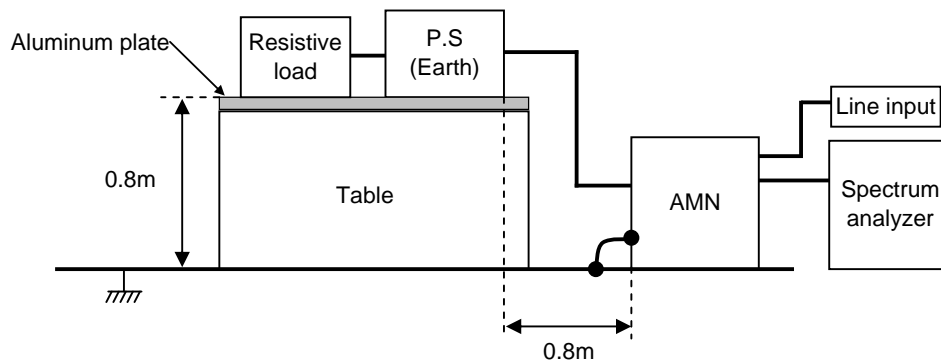
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.25908		VB	37.4	33.1	10.2	47.6	43.3	79	66	31.4	22.7	Pass	
0.65049		VA	33.7	30	10.1	43.8	40.1	73	60	29.2	19.9	Pass	
1.43357		VA	34.6	23.1	10.3	44.9	33.4	73	60	28.1	26.6	Pass	
5.08267		VB	33.9	30.7	10.6	44.5	41.3	73	60	28.5	18.7	Pass	
24.1075		VB	32.2	26.4	11.4	43.6	37.8	73	60	29.4	22.2	Pass	



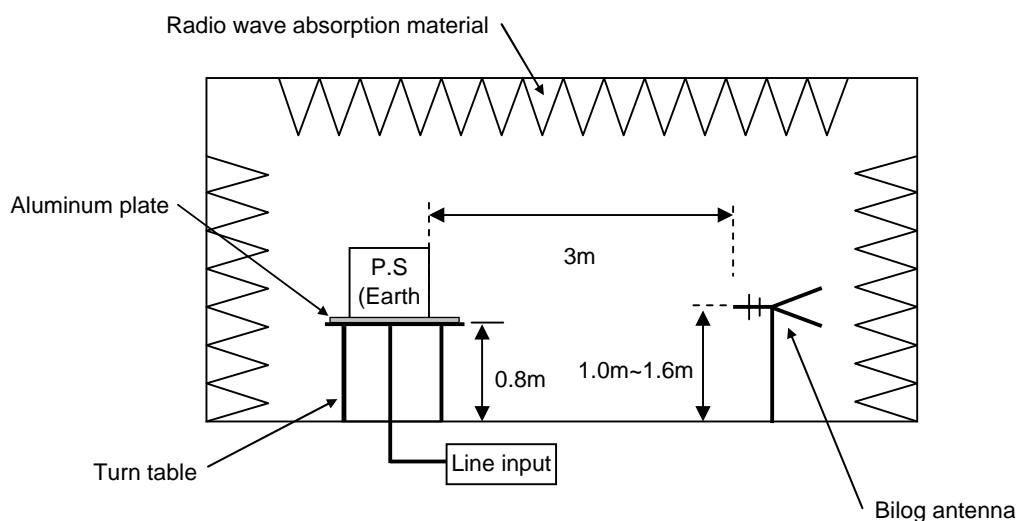
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
64.172	H	Stable	66.6	-22.4		44.2	50	5.8	Pass	138	178	
100.84	H	Stable	60	-18.1		41.9	50	8.1	Pass	150	321	
110.225	V	Stable	59.8	-16.8		43	50	7	Pass	155	349	
139.313	H	Stable	59.5	-16.3		43.2	50	6.8	Pass	143	299	

DATA SHEET		Date	20-Jul-11
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.ARAI

1. Line conduction



2. Radiated emission



Test: EMI

Model Name: SNDPG750+SNDHS250B48+SNDHS100B05+SNDHS100B12+SNDHS100B24+SNDHS100B28

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Test Circuit

